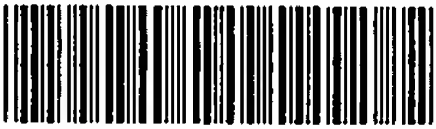




| | | |
|--|---|--|
| Search Notes  | Application/Control No. 10609493 | Applicant(s)/Patent Under Reexamination SHINOTSUKA ET AL. |
| | Examiner Carter, Aaron W | Art Unit 2624 |

| Notes | Date | Examiner |
|---|----------|--------------------|
| EAST Text Search (USPAT, PGPUB, IBM, EPO) See Search History Printout | 10/24/06 | AWC |
| Inventor Name Search (See PALM Search History Printout, Check Marks Indicate Applications Considered) | 10/24/06 | AWC |
| IEEE Text and Author Search, See Search History Printout | 10/24/06 | AWC |
| U.S. Patent and Trademark Office | | Part of Paper No.: |

| | | |
|--|---|--|
| <i>Interference Searched</i>  | Application/Control No. 10609493 | Applicant(s)/Patent Under Reexamination SHINOTSUKA ET AL. |
| | Examiner Carter, Aaron W | Art Unit 2624 |

| Class | SubClass | Date | Examiner |
|-------|----------|------|----------|
|-------|----------|------|----------|

| | |
|----------------------------------|--------------------|
| U.S. Patent and Trademark Office | Part of Paper No.: |
|----------------------------------|--------------------|

| | | |
|--|-----------------------------|---|
| <div>Searched</div> <div></div> | Application/Control No. | Applicant(s)/Patent Under Reexamination |
| | 10609493 | SHINOTSUKA ET AL. |
| | Examiner Carter, Aaron W | Art Unit 2624 |

| Class | SubClass | Date | Examiner |
|-------|----------|----------|----------|
| 382 | 274 | 10/24/06 | AWC |
| 250 | 205 | 10/24/06 | AWC |
| 345 | 20 | 10/24/06 | AWC |
| 348 | 251 | 10/24/06 | AWC |
| 358 | 461 | 10/24/06 | AWC |

| | |
|----------------------------------|--------------------|
| U.S. Patent and Trademark Office | Part of Paper No.: |
|----------------------------------|--------------------|